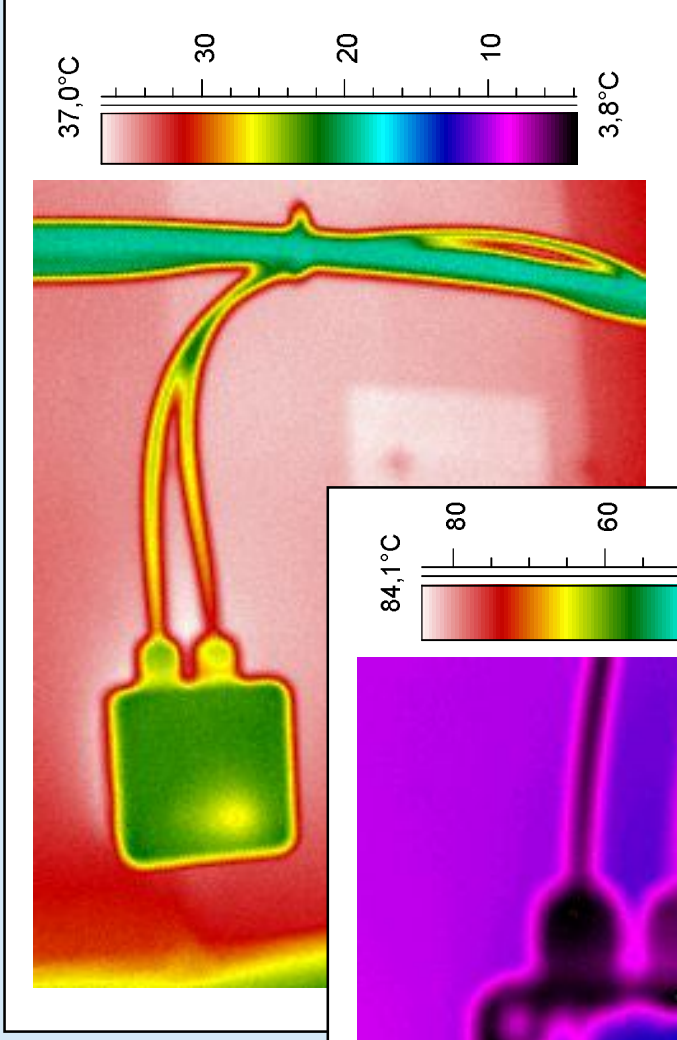
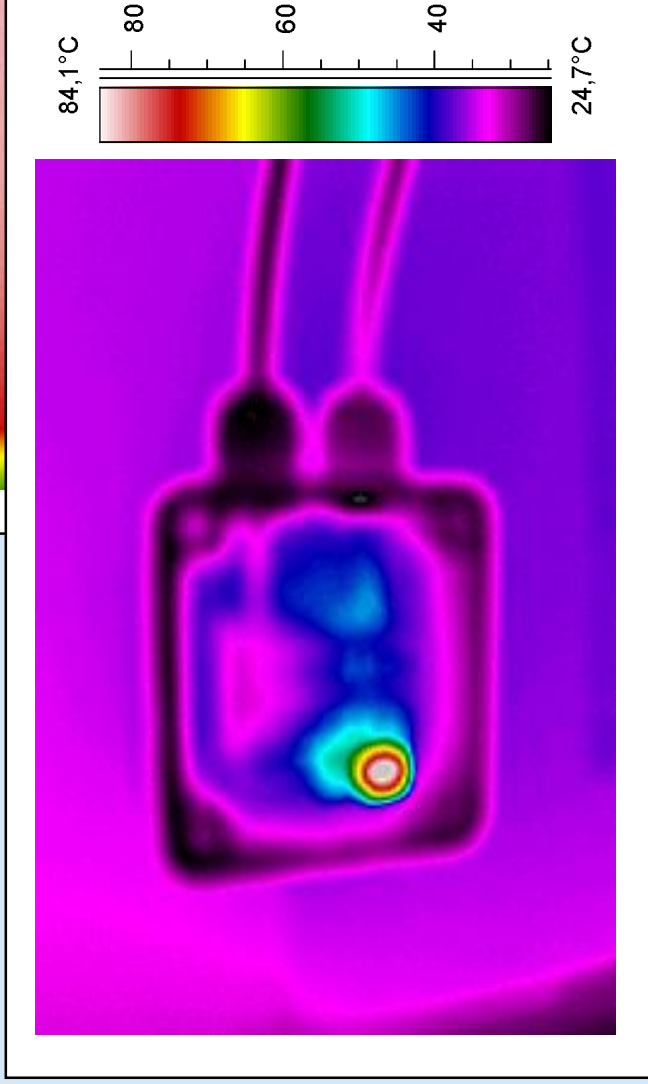


## ■ Bypass diode thermal test Possible problem in field installation

Active by-pass diode  
(closed connection box)



Active by-pass diode  
(connection box with open lid)

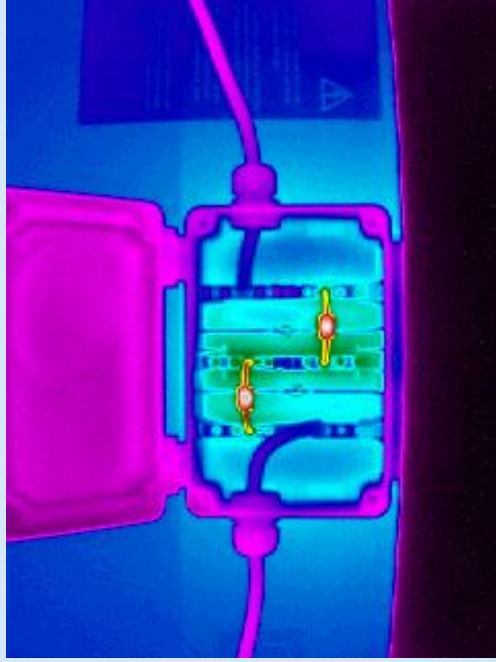


## ■ Bypass diode thermal test

Example of test performance



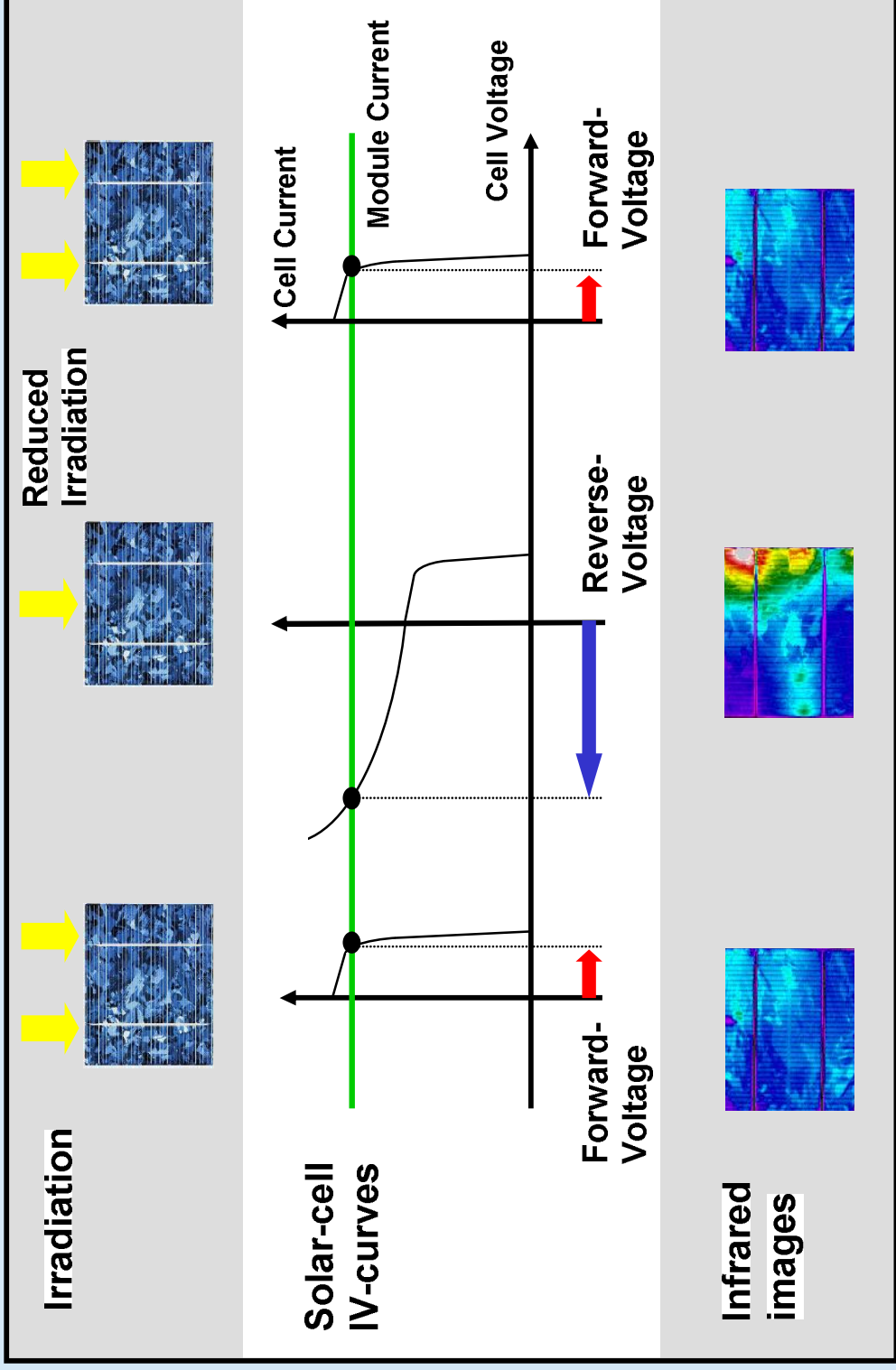
Diode type: 80 SQ 045  
 $T_{j \max} = 175^{\circ}\text{C}$



Current [A]	Box Temperature [°C]	Junction Temperature $T_j$ [°C]
4.88 ( $I_{sc}$ )	128.2	135.2
6.1 ( $1.25 \cdot I_{sc}$ )	144.2	151.2

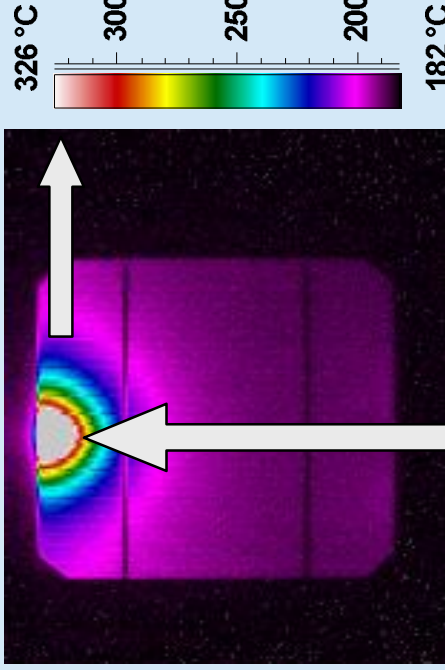
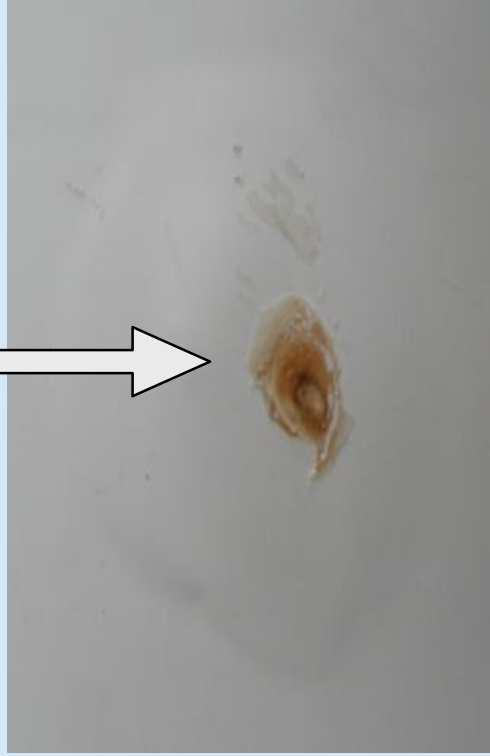
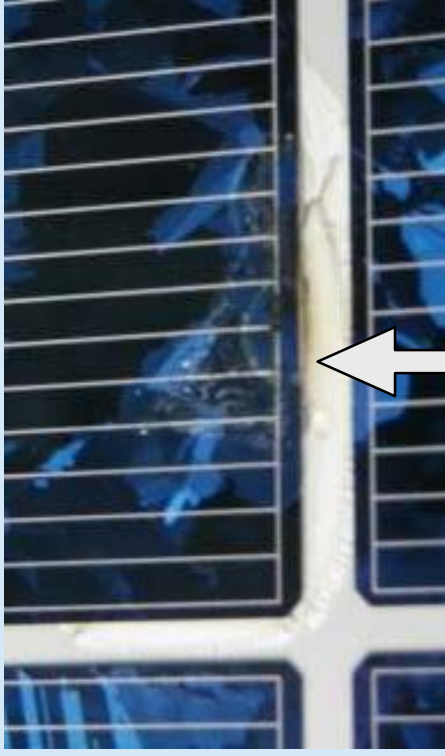
# Hot-Spot endurance test

Problem



## Hot-Spot endurance test

Test failure



Hot-Spots can produce severe visible defects on module front and rear side (temperatures > 300 °C !)

## ■ UV-preconditioning test



### Browning effects of EVA



- Dose UV (280 nm - 400 nm): > 15 kWh/m<sup>2</sup>
- Dose UV-B (280 nm - 320 nm): =3 to 10 % of total UV
- Module temperature: 60 °C

